

**RELIABILITY MONITOR REPORT
FOR**

QFN Package

Dallas Semiconductor

**4401 South Beltwood Parkway
Dallas, TX 75244-3292**

**This Report was prepared by
Dallas Semiconductor Reliability Engineering**

Summary:

The data in the tables that follow was generated as the result of an on-going Package Reliability Monitor. The specific assemblies included in this package monitor are:

ASSY SITE	PINS	PACKAGE
UTL (NSEB) UTAC	10	TDFN (Pb-Free)

The calculated failure rate for this assembly is:

FAILURE RATE: MTTF (YRS): 5288 FITS: 21.6

The parameters used to calculate this failure rate are as follows:

Cf: 60% Ea: 0.7 Tu: 25 °C

The reliability data follows. At the start of this data is a description of the assembly vehicle used to generate this reliability data. The next section is the detailed reliability data for each stress. The reliability data section includes the latest data available. This report covers data between and

Assembly Information:

Package Type: TDFN
Flammability: UL 94-V0
Date Code Range: 0642 to 0642

OPERATING LIFE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	FA NO
HIGH TEMP OP LIFE	0642	DS2786	125C, 5.5 VOLTS	1000 HRS	45	0	
Total:						0	

WE ENDURANCE AND DATA RET'N

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	FA NO
WRITE CYCLE STRESS (KCYS)	0642	DS2786	50 C, 5.5 VOLTS (PSA), 15.0 VOLTS (PSB)	10 KCYS	77	0	
STORAGE LIFE			150C	1000 HRS	77	0	
WRITE CYCLE STRESS (KCYS)	0642	DS2786	50 C, 5.5 VOLTS (PSA), 15.0 VOLTS (PSB)	1 KCYS	77	0	
STORAGE LIFE			150C	1000 HRS	77	0	
WRITE CYCLE STRESS (CYS)	0642	DS2786	50 C, 5.5 VOLTS (PSA), 15.0 VOLTS (PSB)	100 CYS	77	0	
STORAGE LIFE			150C	1000 HRS	77	0	
Total:						0	

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